

Search Notes**Application/Control No.**

10/608,771

Examiner

Duc M. Nguyen

Applicant(s)/Patent under Reexamination

EIDEN, NIKO

Art Unit

2685 2618

SEARCHED

Class	Subclass	Date	Examiner
455	567		
	414.1		
	414.2		
	415		
	401		
340	7.52		
	7.6	10/27/05 4/11/06	DN DN
<i>Updated</i>			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	10/22/2005	DN
EAST	10/27/2005	DN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner